

Device Modeling Report

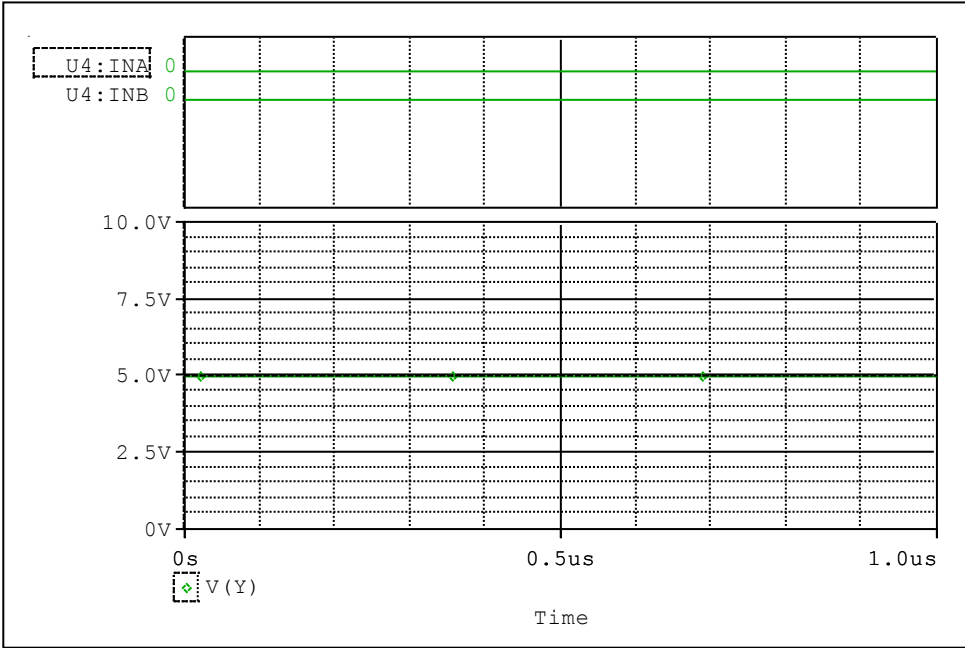
COMPONENTS : CMOS DIGITAL INTEGRATED CIRCUIT
PART NUMBER : TC7SZ00AFE
MANUFACTURER : TOSHIBA



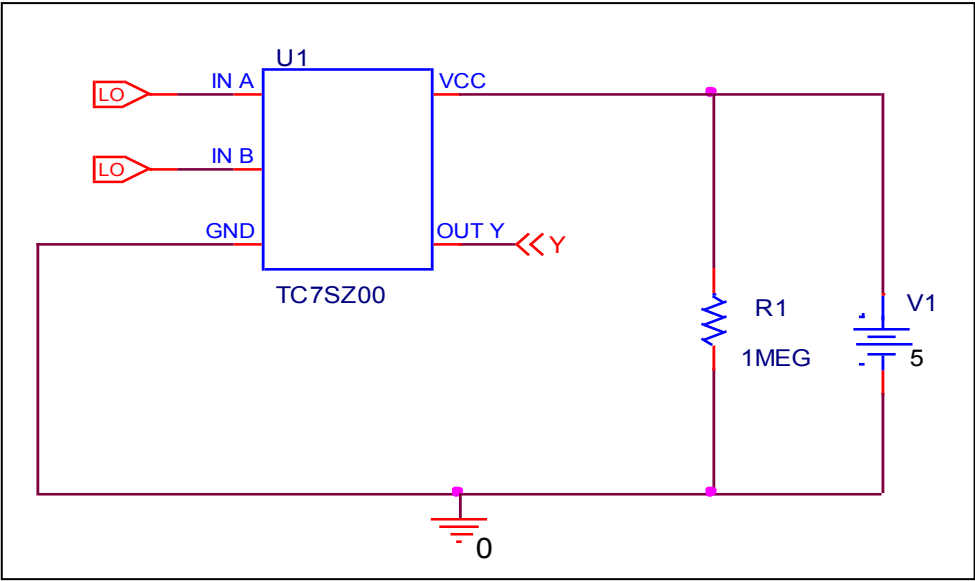
Bee Technologies Inc.

Truth Table

Circuit simulation result



Evaluation circuit

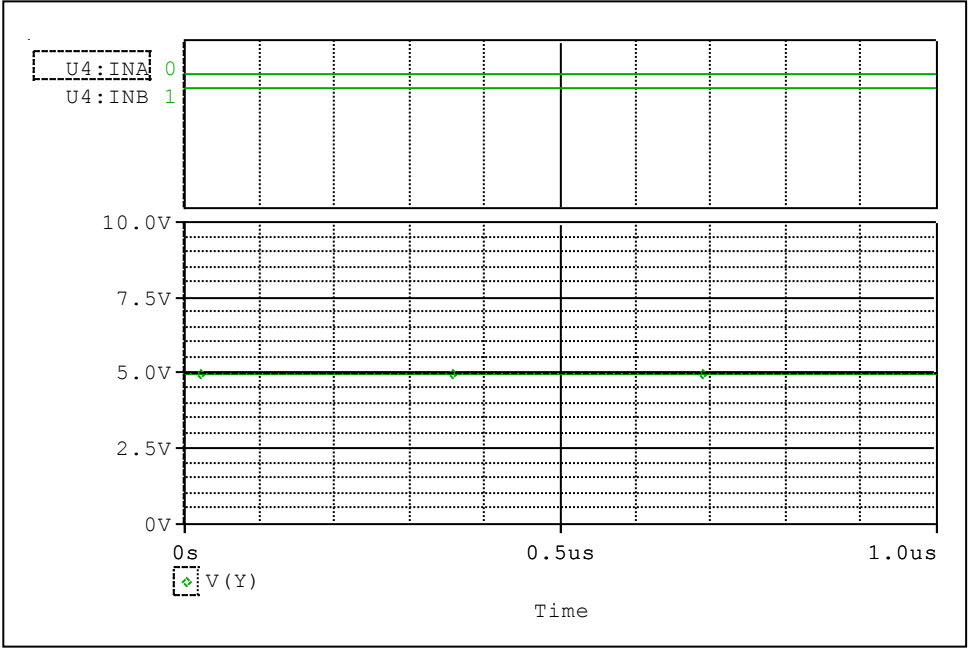


Comparison table

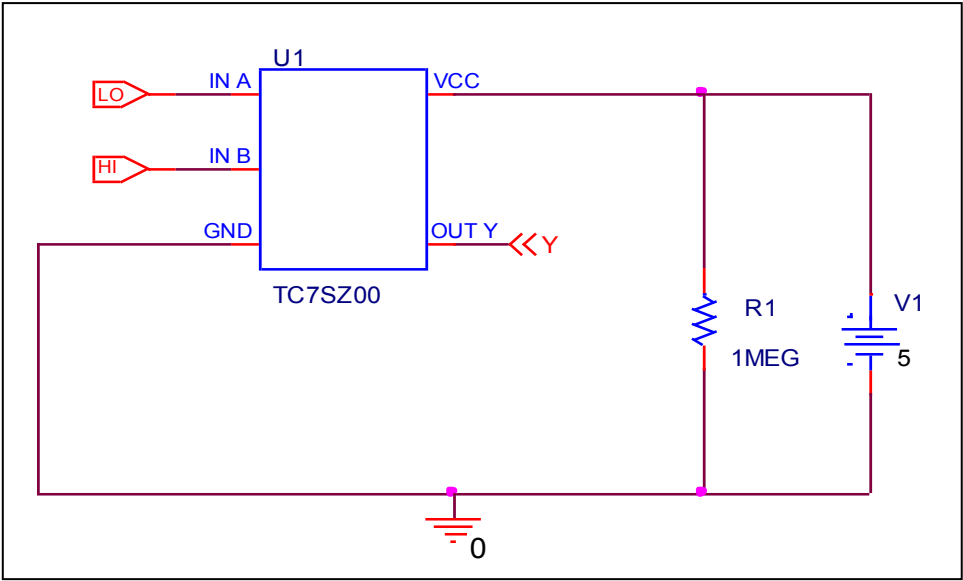
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
L	L	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

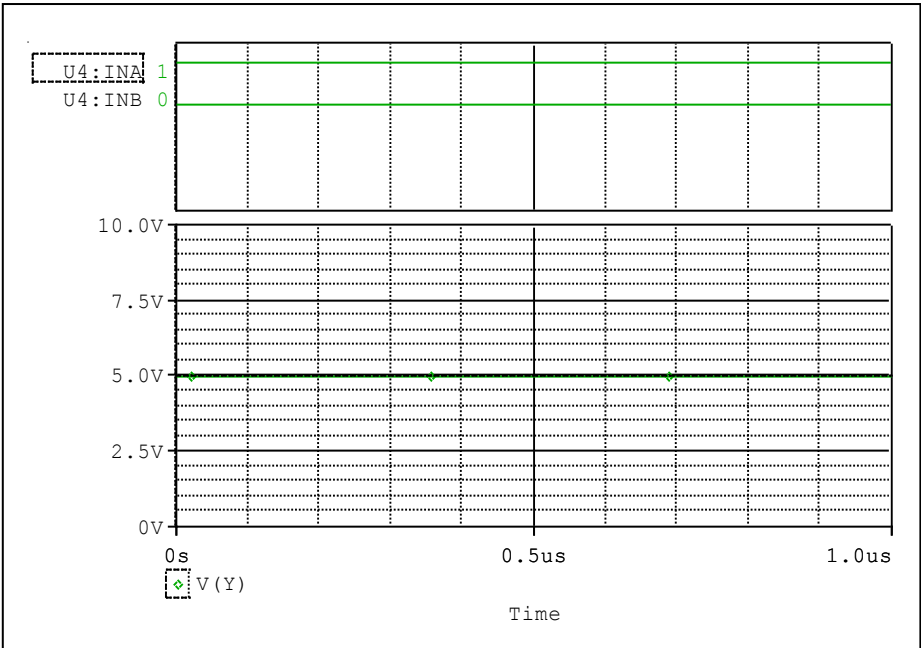


Comparison table

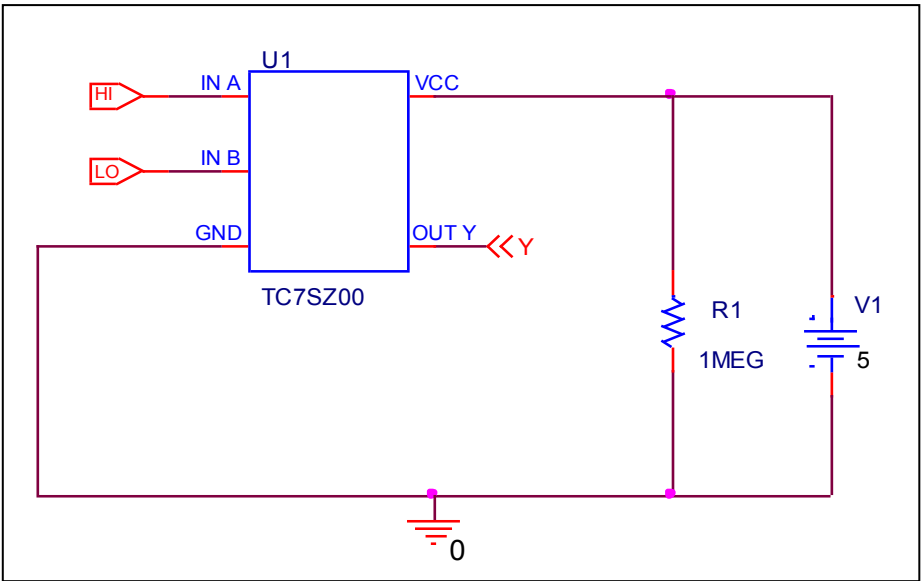
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
L	H	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

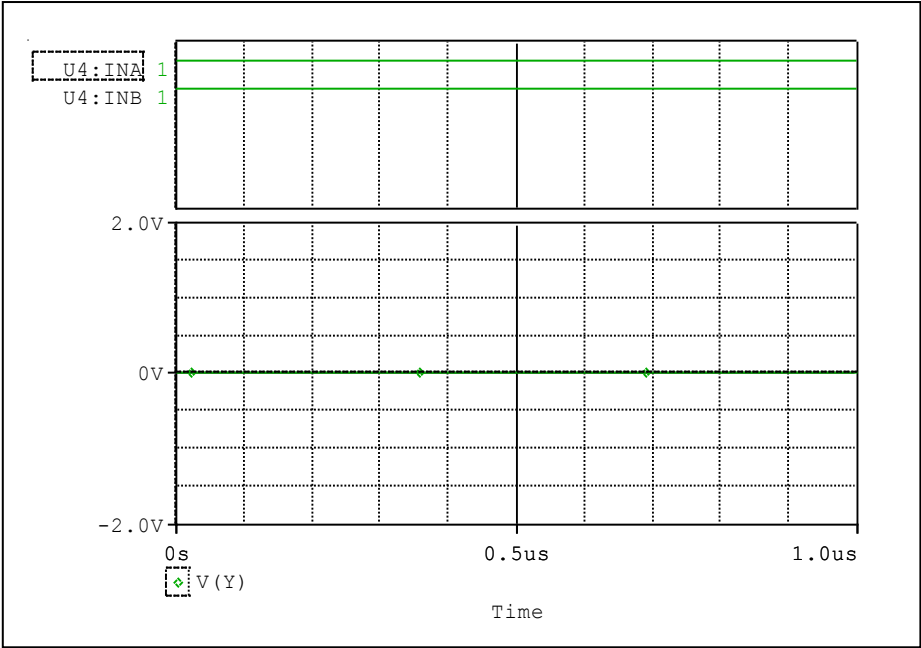


Comparison table

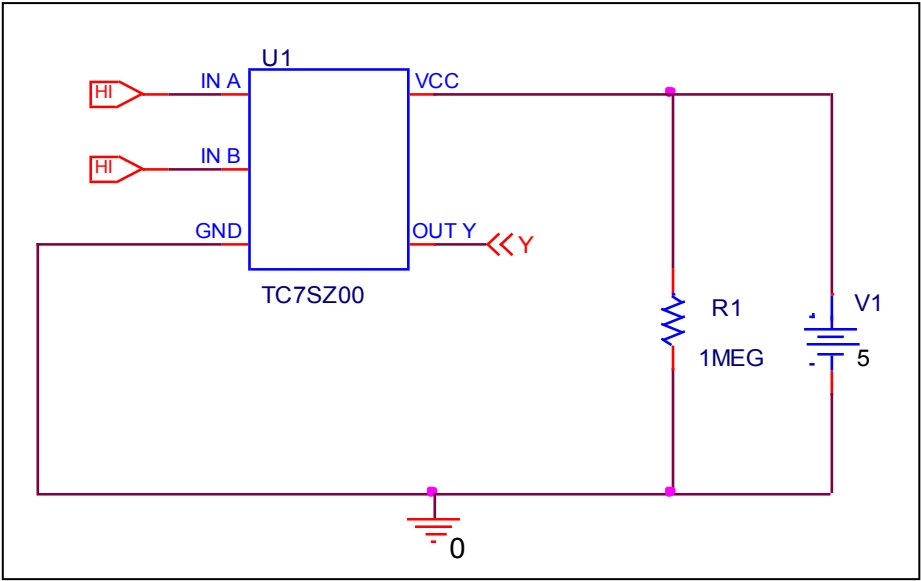
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
H	L	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

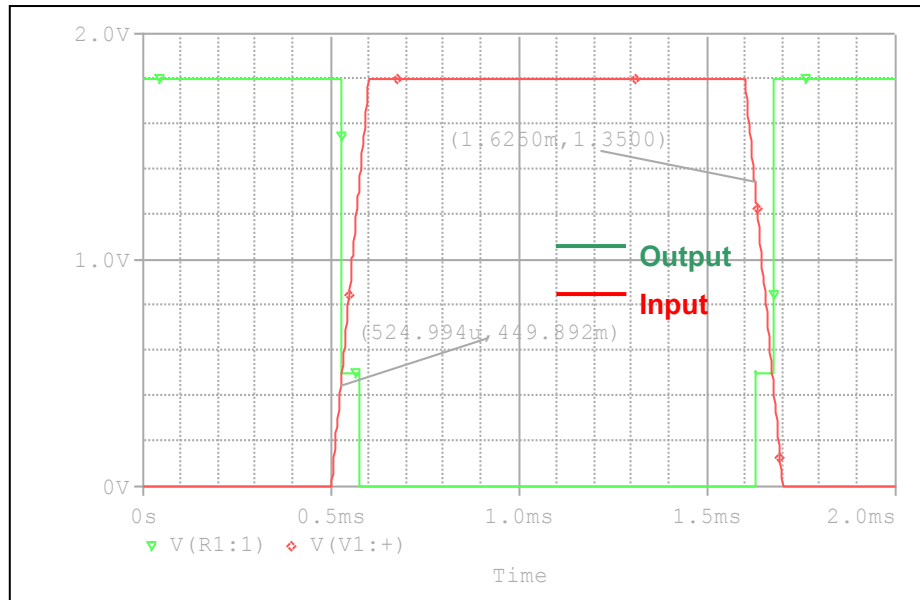


Comparison table

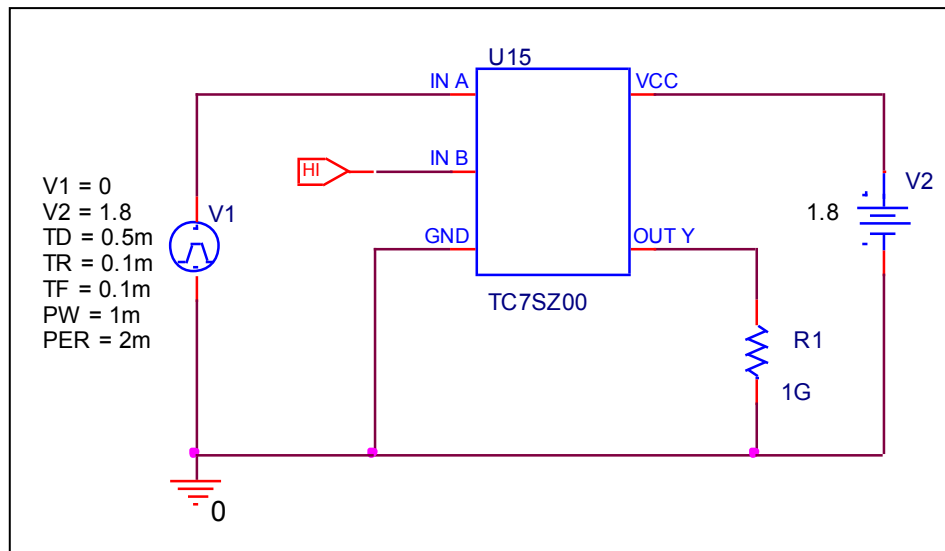
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
H	H	L	L	0

High Level and Low Level Input Voltage ($V_{CC}=1.8V$)

Circuit simulation result



Evaluation circuit

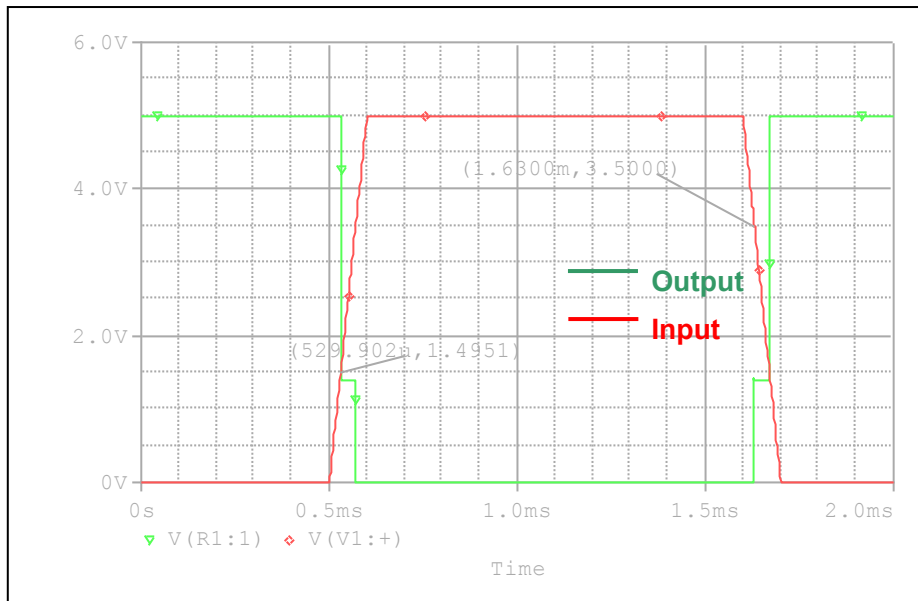


Comparison table

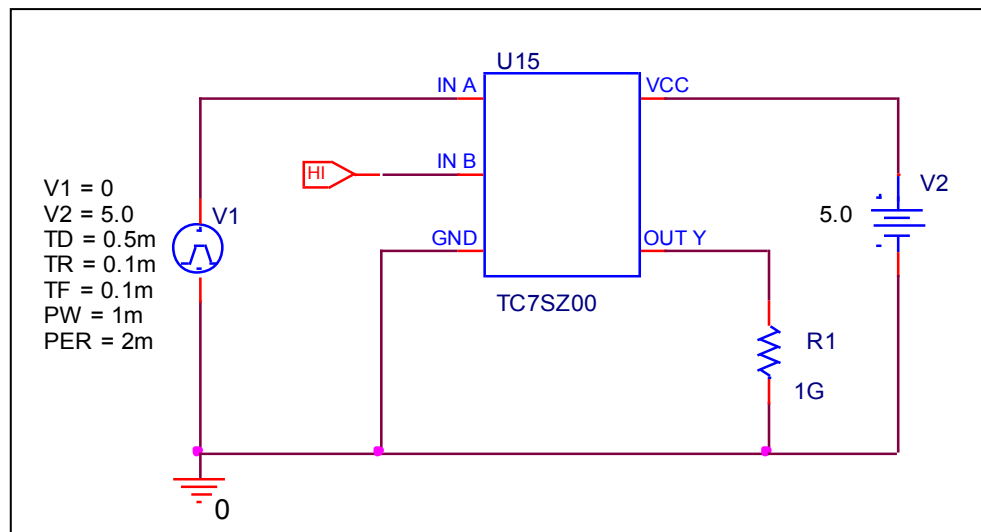
$V_{CC} = 1.8V$	Measurement	Simulation	%Error
Min V_{IH} (V) = $(0.75 \cdot V_{CC})$ V	1.35	1.35	0.000
Max V_{IL} (V) = $(0.25 \cdot V_{CC})$ V	0.45	0.449892	-0.024

High Level and Low Level Input Voltage ($V_{CC}=5.0V$)

Circuit simulation result



Evaluation circuit

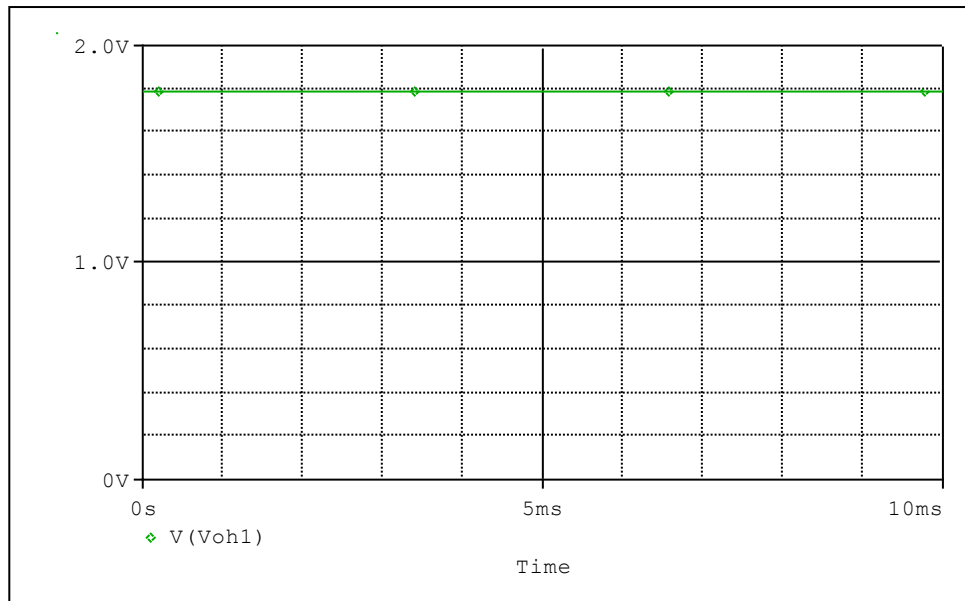


Comparison table

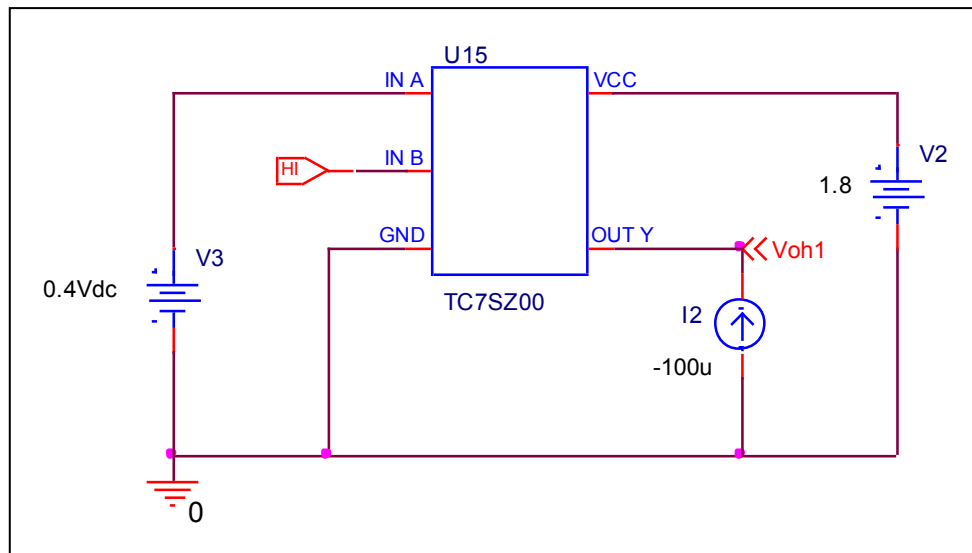
$V_{CC} = 5.0V$	Measurement	Simulation	%Error
Min V_{IH} (V) = $(0.7 \cdot V_{CC})$ V	3.5	3.5	0.000
Max V_{IL} (V) = $(0.3 \cdot V_{CC})$ V	1.5	1.4951	-0.327

High Level Output Voltage ($V_{CC} = 1.8\text{ V}$)

Circuit simulation result



Evaluation circuit

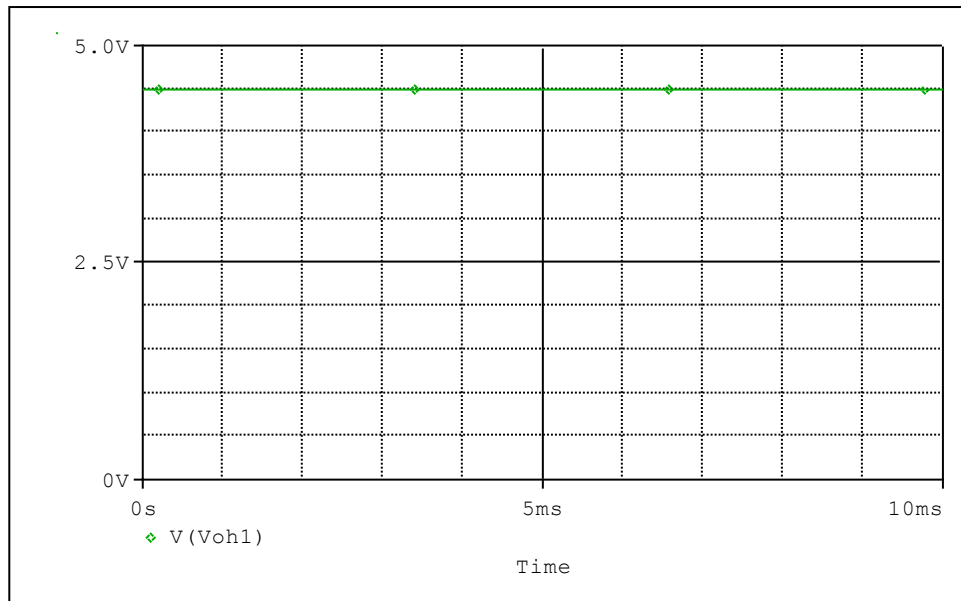


Comparison table

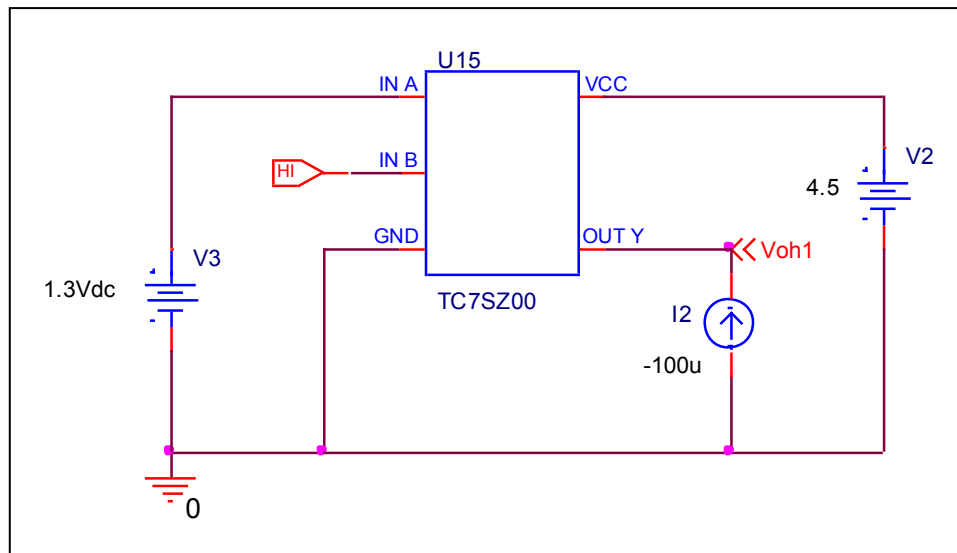
$V_{CC} = 1.8\text{ V}$ @ $V_{IN} = V_{IL}$; $I_{OH} = -100\mu\text{ A}$	Measurement	Simulation	%Error
$V_{OH}\text{ (V)}$	1.8	1.7989	-0.061

High Level Output Voltage ($V_{CC} = 4.5\text{ V}$)

Circuit simulation result



Evaluation circuit

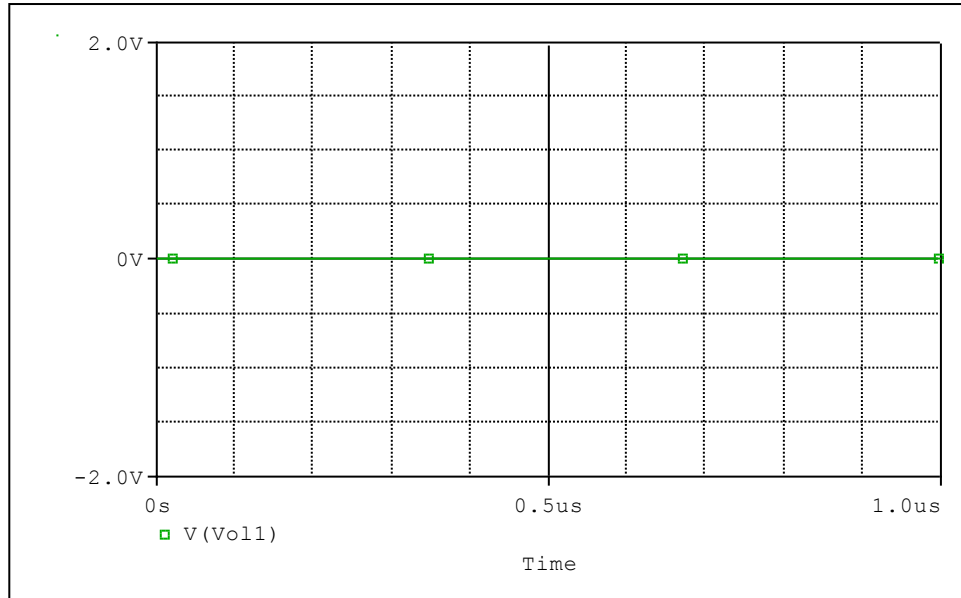


Comparison table

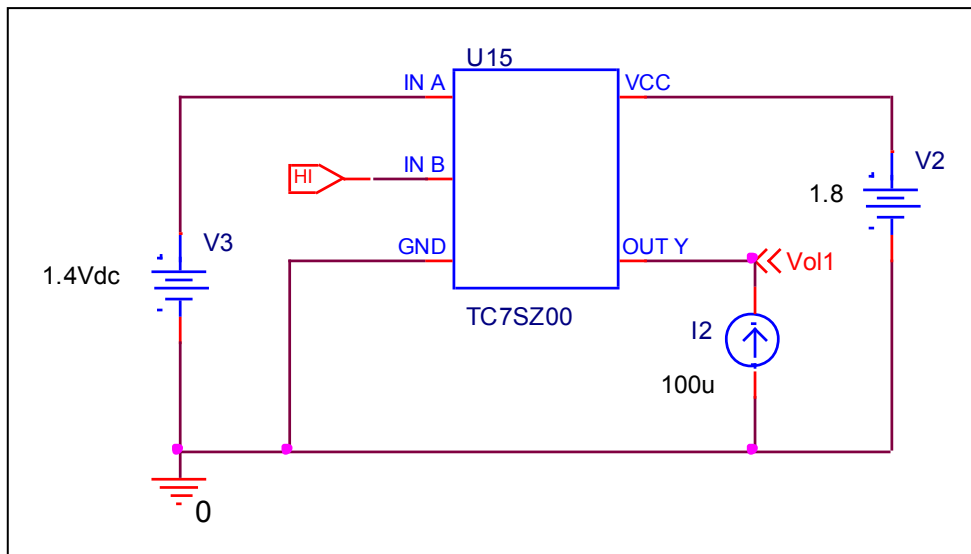
$V_{CC} = 4.5V$ @ $V_{IN} = V_{IL}$; $I_{OH} = -100\mu A$	Measurement	Simulation	%Error
V_{OH} (V)	4.5	4.4976	-0.053

Low Level Output Voltage ($V_{CC} = 1.8\text{ V}$)

Circuit simulation result



Evaluation circuit

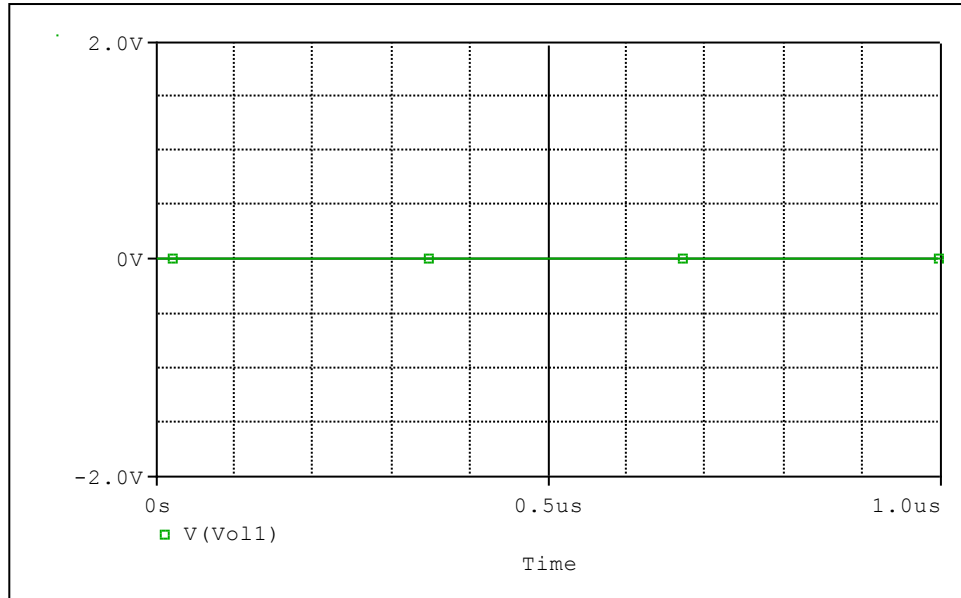


Comparison table

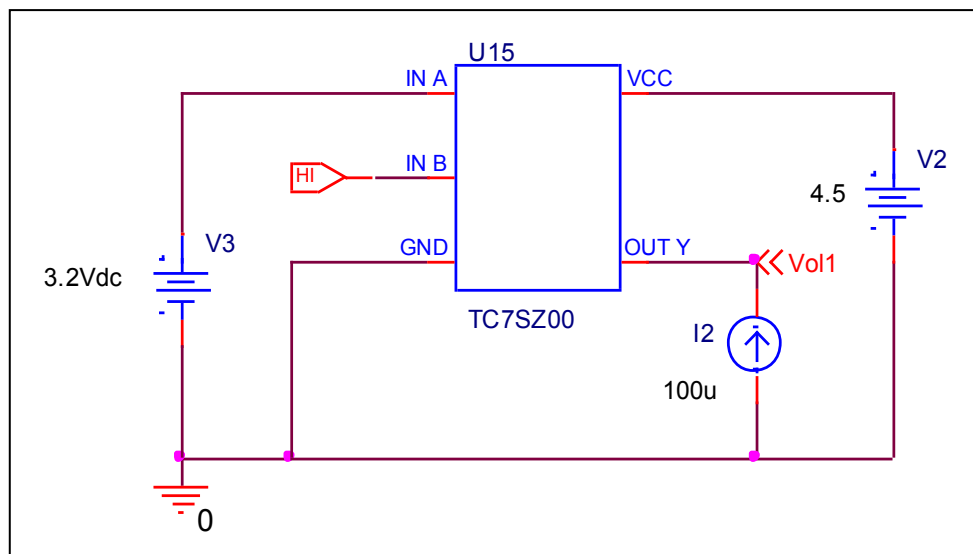
$V_{CC} = 1.8\text{ V}$ @ $V_{IN} = V_{IH}$; $I_{OL} = 100\mu\text{A}$	Measurement	Simulation	%Error
$V_{OL} \text{ (V)}$	0	0	0

Low Level Output Voltage ($V_{CC} = 4.5\text{ V}$)

Circuit simulation result



Evaluation circuit

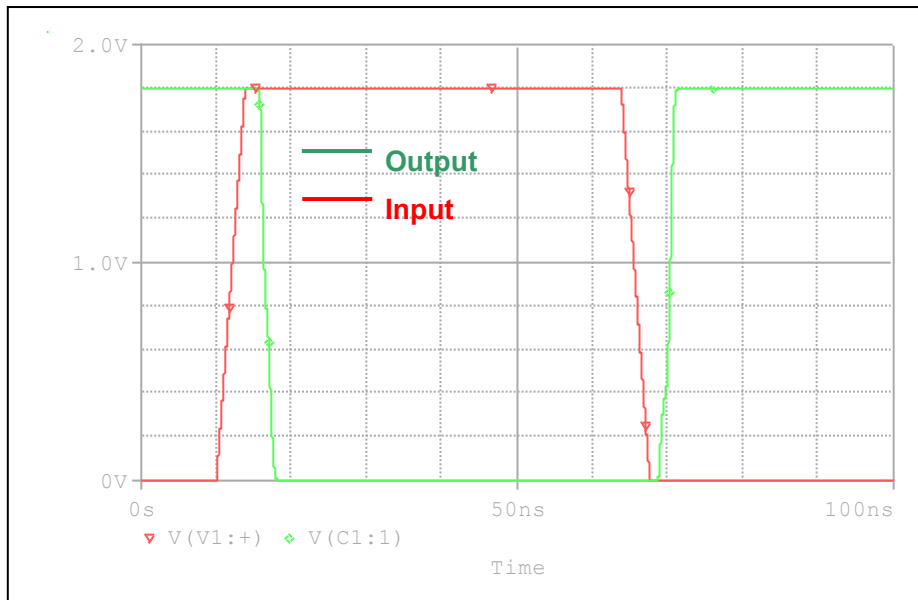


Comparison table

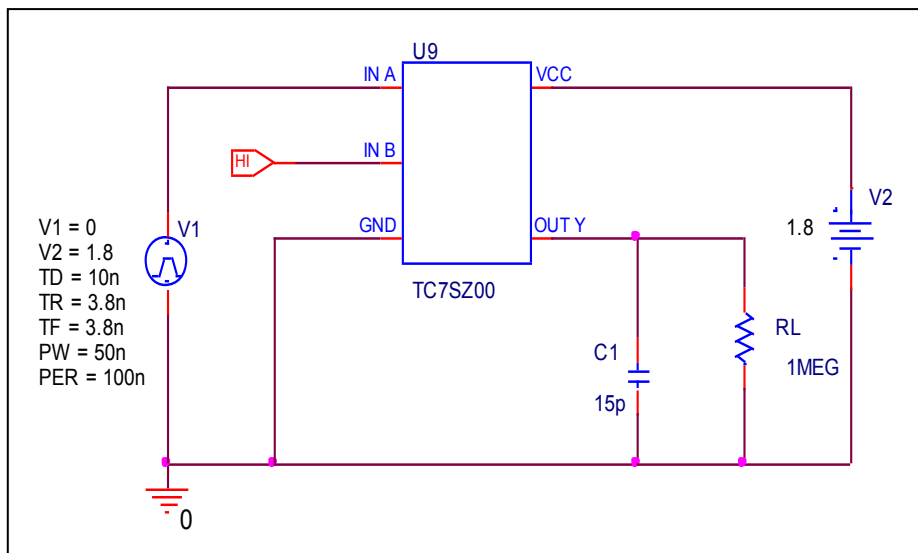
$V_{CC} = 4.5\text{ V}$ @ $V_{IN} = V_{IH}$; $I_{OL} = 100\mu\text{A}$	Measurement	Simulation	%Error
$V_{OL}\text{ (V)}$	0	0	0

Propagation Delay Time ($V_{CC} = 1.8\text{ V}$)

Circuit simulation result



Evaluation circuit

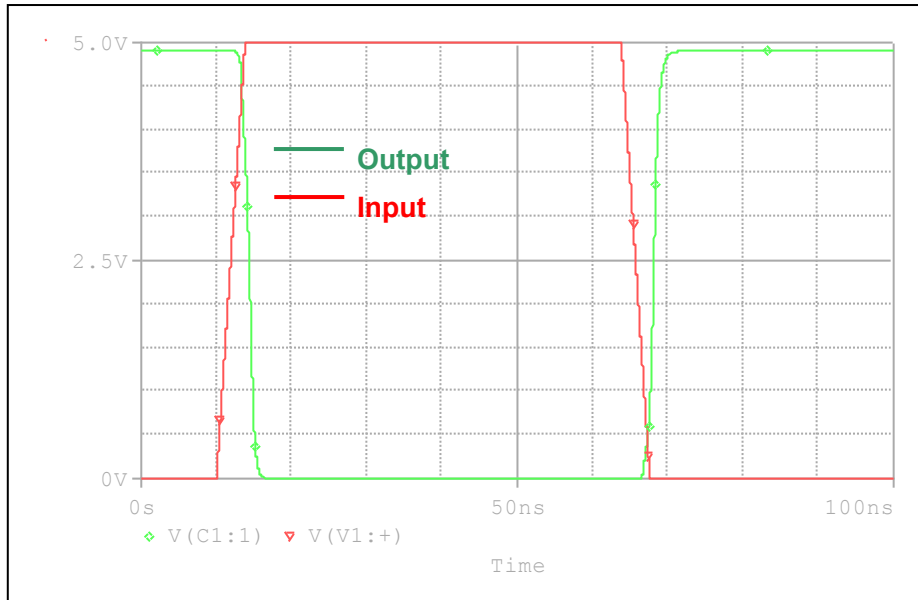


Comparison table $C_L = 15\text{ pF}$, $R_L = 1\text{ M}\Omega$

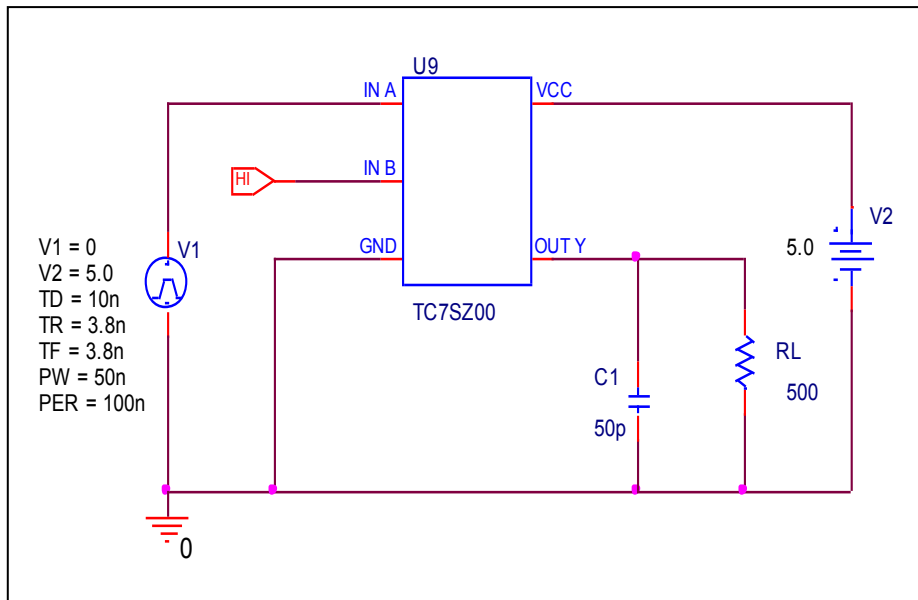
$V_{CC} = 1.8\text{V}$, $t_r = t_f = 3\text{ ns}$	Measurement	Simulation	%Error
$t_{pLH}\text{ (ns)}$	4.5	4.5716	1.591
$t_{pHL}\text{ (ns)}$	4.5	4.5448	0.996

Propagation Delay Time ($V_{CC} = 5.0\text{ V}$)

Circuit simulation result



Evaluation circuit



Comparison table $C_L = 50\text{ pF}$, $R_L = 500\Omega$

$V_{CC} = 5.0\text{V}$, $t_r = t_f = 3\text{ ns}$	Measurement	Simulation	%Error
$t_{pLH}\text{ (ns)}$	2.4	2.4418	1.742
$t_{pHL}\text{ (ns)}$	2.4	2.4596	2.483